

FIG. 4 is a block diagram of a system 100 illustrating a scan chain architecture. The system 100 includes a TOP block 101, a CORE block 102, and a TAP block 106. The TOP block 101 includes a BIST block 118, a CD Flop block 120, and a LB Chain block 122. The CORE block 102 includes a BIST block 124, a CD Flop block 126, and a LB Chain block 128. The TAP block 106 includes a BIST block 130, a CD Flop block 132, and a LB Chain block 134. The system 100 is configured to perform a scan operation, where data is shifted through the scan chains of the TOP, CORE, and TAP blocks. The BIST blocks are used to generate test patterns, and the CD Flop blocks are used to capture the test results. The LB Chain blocks are used to load the test patterns into the scan chains. The system 100 is also configured to perform a bypass operation, where data is shifted directly from the TAP block to the CORE block without passing through the scan chains. The BIST blocks are used to generate test patterns, and the CD Flop blocks are used to capture the test results. The LB Chain blocks are used to load the test patterns into the scan chains. The system 100 is also configured to perform a test operation, where data is shifted through the scan chains of the TOP, CORE, and TAP blocks. The BIST blocks are used to generate test patterns, and the CD Flop blocks are used to capture the test results. The LB Chain blocks are used to load the test patterns into the scan chains. The system 100 is also configured to perform a test operation, where data is shifted through the scan chains of the TOP, CORE, and TAP blocks. The BIST blocks are used to generate test patterns, and the CD Flop blocks are used to capture the test results. The LB Chain blocks are used to load the test patterns into the scan chains.

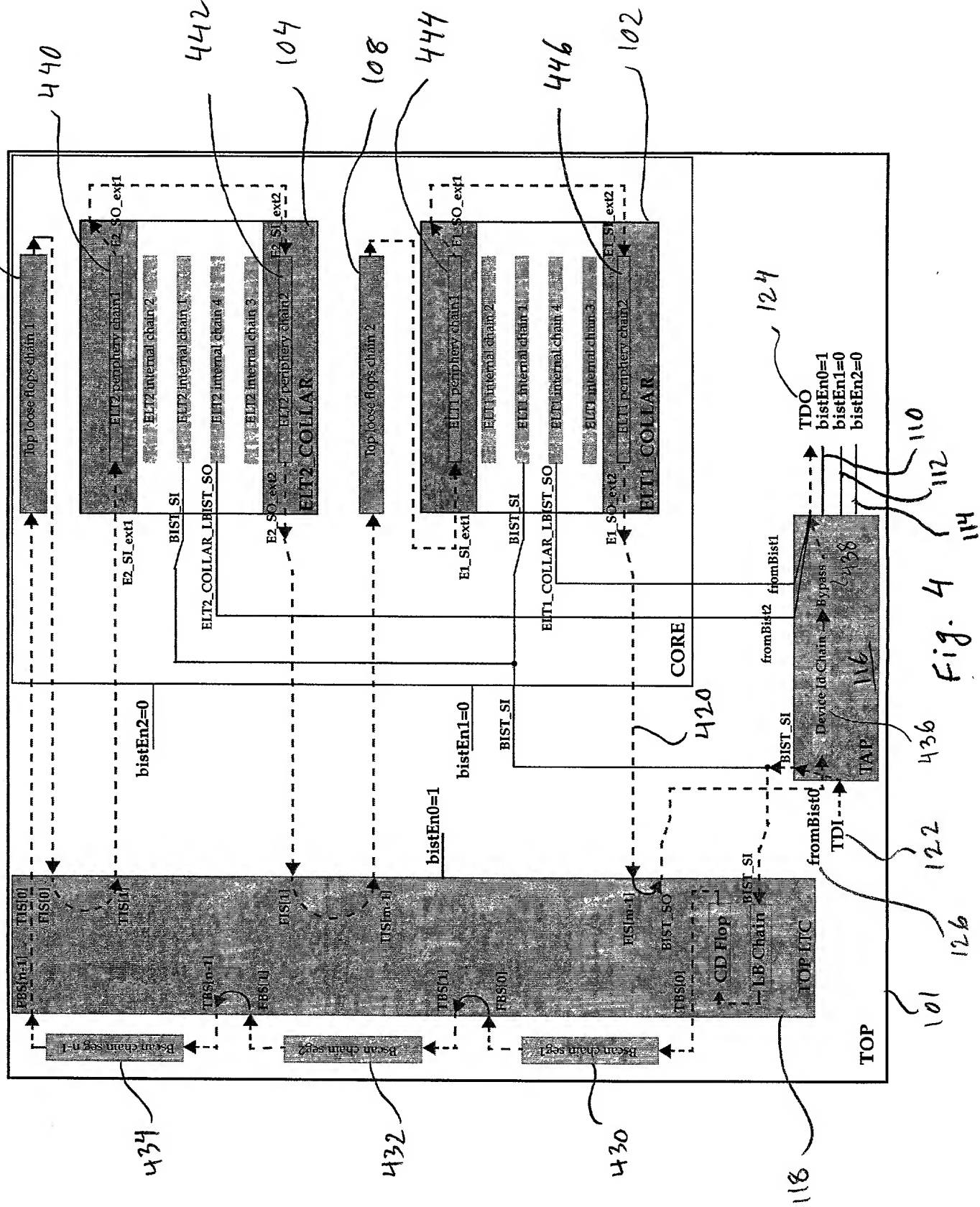


Fig. 4

